

Amendments to the Claims:

This listing of claims will replace all prior versions, and listings of claims in the application:

Listing of Claims:

1 1. (currently amended): A measuring system for detecting defects of an
2 object having at least a first and a second layer, which system comprises at least one light source
3 arranged to illuminate the object with incident light, ~~an a single two-dimensional~~ imaging sensor
4 arranged to detect reflected light emanating from the object and to convert the detected light into
5 electrical charges, and~~[,]~~ means for creating a representation of the object according to the
6 electrical charges, wherein the system comprises means for obtaining information from the
7 representation ~~on of~~ light scattered by entering the object and emerging from the object at a
8 different location from the entering location after being spread in the first layer and the second
9 layer of the object from the representation, and~~[,]~~ means for comparing the information to
10 stored information in order to detect defects on the object.

1 2. (previously presented): A measuring system according to claim 1,
2 wherein the measuring system and/or the object is/are arranged to move in relation to one
3 another in a predefined direction of movement.

1 3. (previously presented): A measuring system according to claim 1,
2 wherein the incident light is arranged to have limited dispersion in a predefined direction.

1 4. (previously presented): A measuring system according to claim 3,
2 wherein the incident light is a linear light.

1 5. (previously presented): A measuring system according to claim 1,
2 wherein the system further comprises means for obtaining information on the geometric profile
3 of the object from the representation.

1 6. (previously presented): A measuring system according to claim 5,
2 wherein the system comprises means for obtaining information on the geometric profile of the
3 first layer of the object from the representation.

1 7. (previously presented): A measuring system according to claim 5,
2 wherein the system comprises means for obtaining information on the geometric profile of the
3 second layer of the object from the representation.

1 8. (previously presented): A measuring system according to claim 1,
2 wherein the light source comprises a polarizer arranged to facilitate the distinction between light
3 reflected on the object and scattered light in the object.

1 9. (previously presented): A measuring system according to claim 1,
2 wherein the first layer consist of a transparent or semi-transparent material.

1 10. (previously presented): A measuring system according to claim 1,
2 wherein the object is a package wrapped in a protective material.

1 11. (currently amended): A method for detecting defects of an object having
2 at least a first and a second layer by means of a measuring system, in which method the object is
3 illuminated by means of incident light, and light reflected and emanating from the object is
4 detected by means of ~~an~~ a single two-dimensional imaging sensor in which the detected light is
5 converted into electrical charges, according to which a representation of the object is created,
6 wherein information is obtained from the representation of ~~an~~ light scattered by entering the
7 object and emerging from the object at a different location from the entering location after being
8 spread in the first layer and the second layer of the object is ~~obtained from the representation~~ and
9 wherein the information is compared to stored information in order to detect defects on the
10 object.

1 12. (previously presented): A method according to claim 11, wherein the
2 measuring system and/or the object is/are moved in relation to one another in a predefined
3 direction of movement.

1 13. (previously presented): A method according to claim 11, wherein also
2 information on the geometric profile of the object is obtained from the representation.

1 14. (previously presented): A method according to claim 13, wherein
2 information on the geometric profile of the first layer of the object is obtained from the
3 representation.

1 15. (previously presented): A method according to claim 13, wherein
2 information on the geometric profile of the second layer of the object is obtained from the
3 representation.

1 16. (previously presented): A method according to claim 11, wherein the
2 incident light is polarized and wherein the polarized incident light is used to distinguish between
3 reflected light on the object and scattered light in the object.